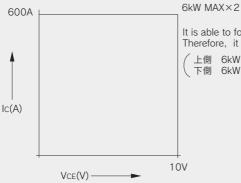
AGING TEST SYSTEM エージングテストシステム



- ●SCTS60Z is the aging test system to observe deterioration of IGBT module. This system judges the deterioration by forcing power of 6kW at maximum and measures leakage current before and after forcing. D.U.T. transportation and heat-up system are in one unit in the system and pass devices and fail devices are stored to the discharge area.
- ●本システムはIGBTモジュールの劣化状態を観測するエージングテストシステムです。 最大6kWの電力を印加し、印加前後のリーク電流を測定し劣化状態を判定します。 製品写真はD.U.T.の搬送およびヒートアップ機構と一体となっていて、良品と不良 品を排出部に収納します。

*This system is integrated with Jig. *治具と一体型のシステムです。

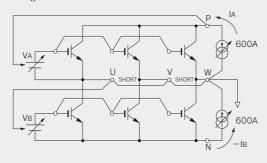
Forcing Power Range

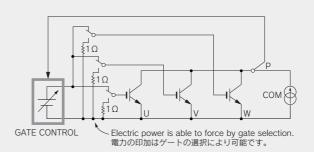


It is able to force power 6kW from each upper and lower side to IGBT module. Therefore, it is able to force power 12kW totally.

上側 6kW MAX 下側 6kW MAX 上下合わせると最大12kW

Forcing Power Method





| MODEL | SCTS60Z | | | |
|---------------------|--|--|--------------|--|
| MEASURABLE DEVICE | | IGBT | | |
| [SETTING RANGE] | ICP | 1A~600A | 1A STEP | |
| | VCE | 1V~10V | 1V STEP | |
| | TEST TIME | 0.01sec~9.99sec | 0.01sec STEP | |
| | TOTAL TIME | 0.1sec~99.9sec | 0.1sec STEP | |
| [ICES TEST] | VL | 1V~50V | 1V STEP | |
| | ICES | $0\mu\text{A}{\sim}999.9\mu\text{A},0\text{mA}{\sim}9.99\text{mA}$ | 2 ranges | |
| | TEST TIME | 0.01sec~9.99sec | 0.01sec STEP | |
| [IGEE TEST] | VL | 1V~50V | 1V STEP | |
| | IGES | 0μΑ~9.999μΑ, 0μΑ~99.99μΑ | 2 ranges | |
| | TEST TIME | 0.01sec~9.99sec | 0.01sec STEP | |
| DIMENSIONS & WEIGHT | | | | |
| MAIN UNIT | 550(W)×1220(D)×1700(H)···1285kg(2sets) | | | |
| TEST HEAD | 430(W)×700(D)×245(H)···53kg | | | |